

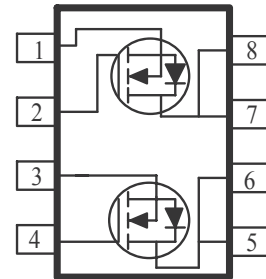
Dual N-Channel 20-V (D-S) MOSFET

These miniature surface mount MOSFETs utilize High Cell Density process. Low $r_{DS(on)}$ assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry. Typical applications are PWMDC-DC converters, power management in portable and battery-powered products such as computers, printers, battery charger, telecommunication power system, and telephones power system.

- Low $r_{DS(on)}$ Provides Higher Efficiency and Extends Battery Life
- Miniature SO-8 Surface Mount Package Saves Board Space
- High power and current handling capability
- Low side high current DC-DC Converter applications

PRODUCT SUMMARY

V_{DS} (V)	$r_{DS(on)}$ m(Ω)	I_D (A)
20	58 @ $V_{GS} = 4.5V$	5.0
	82 @ $V_{GS} = 2.5V$	4.2



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter		Symbol	Limit	Units
Drain-Source Voltage		V _{DS}	20	V
Gate-Source Voltage		V _{GS}	± 12	
Continuous Drain Current ^a	T _A =25 ^o C	I _D	5.0	A
	T _A =70 ^o C		4.1	
Pulsed Drain Current ^b		I _{DM}	± 30	
Continuous Source Current (Diode Conduction) ^a		I _S	1.7	A
Power Dissipation ^a	T _A =25 ^o C	P _D	2.1	W
	T _A =70 ^o C		1.3	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Maximum	Units
Maximum Junction-to-Ambient ^a	t <= 10 sec	R _{0JA}	62.5	°C/W
	Steady State		80	°C/W

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- Pulse width limited by maximum junction temperature

SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ	Max	
Static						
Gate-Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 uA	0.7			
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 12 V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 16 V, V _{GS} = 0 V			1	uA
		V _{DS} = 16 V, V _{GS} = 0 V, T _J = 55°C			25	
On-State Drain Current ^A	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 4.5 V	20			A
Drain-Source On-Resistance ^A	r _{DS(on)}	V _{GS} = 4.5 V, I _D = 5 A			58	mΩ
		V _{GS} = 2.5 V, I _D =4.2 A			82	
Forward Tranconductance ^A	g _{fs}	V _{DS} = 15 V, I _D = 5 A		22		S
Diode Forward Voltage	V _{SD}	I _S = 1.7 A, V _{GS} = 0 V		0.7		V
Dynamic ^b						
Total Gate Charge	Q _g	V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 5 A		7.5		nC
Gate-Source Charge	Q _{gs}			0.6		
Gate-Drain Charge	Q _{gd}			1.0		
Turn-On Delay Time	t _{d(on)}	V _{DD} = 15 V, R _L = 15 Ω , I _D = 1 A, V _{GEN} = 4.5 V		22		nS
Rise Time	t _r			40		
Turn-Off Delay Time	t _{d(off)}			50		
Fall-Time	t _f			20		
Source-Ddrain Reverse Recovery Time	t _{rr}	I _F = 1.7 A, di/dt = 100 A/uS		40		

Notes

- Pulse test: $PW \leq 300\mu\text{s}$ duty cycle $\leq 2\%$.
- Guaranteed by design, not subject to production testing.